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				Application Number	10/825,486
<b>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</b>  (use as many sheets as necessary)				Filing Date	April 16, 2004
				First Named Inventor	Lee, Yun Bok
				Art Unit	2871
				Examiner Name	Tai V. Duong
Sheet	1	of	1	Attorney Docket Number	8733.1026

U.S. PATENT DOCUMENTS					
Examiner Initials*	Cite No. <sup>1</sup>	Document Number Number-Kind Code <sup>2</sup> (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
	AA	<del>6243154 B1</del>		ALREADY OF RECORD	
		<del>5977562A</del>		ALREADY OF RECORD	
TD		6433764 B1	08-2002	HEB GUCHI ET AL.	
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FOREIGN PATENT DOCUMENTS						
Examiner Initials*	Cite No. <sup>1</sup>	Foreign Patent Document	Publication Date	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T <sup>5</sup>
		Country Code <sup>2</sup> -Number <sup>3</sup> -Kind Code <sup>4</sup> (if known)	MM-DD-YYYY			
	BA	<del>Japan - 00-230344</del> <b>ALREADY OF RECORD</b>	<del>00-05-1987</del>	<del>Semiconductor Energy Lab Co. Ltd</del>	<del>English Abstract</del>	
TD		Japan - 2003-186017	07-03-2003	Fujitsu Display Technologies Corp	English Abstract	
TD		Japan 2000-206553	07-28-2000	Semiconductor Energy Lab Co Ltd	English Abstract	
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TD		Japan - 11-174482	07-02-1999	Sharp Corp	English Abstract	

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NON PATENT LITERATURE DOCUMENTS			
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Examiner Signature	Tai Duong	Date Considered	1/17/07
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